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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	516096
Number of I/O	620
Number of Gates	3000000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TJ)
Package / Case	896-BGA
Supplier Device Package	896-FBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/m1a3pe3000l-fg896m

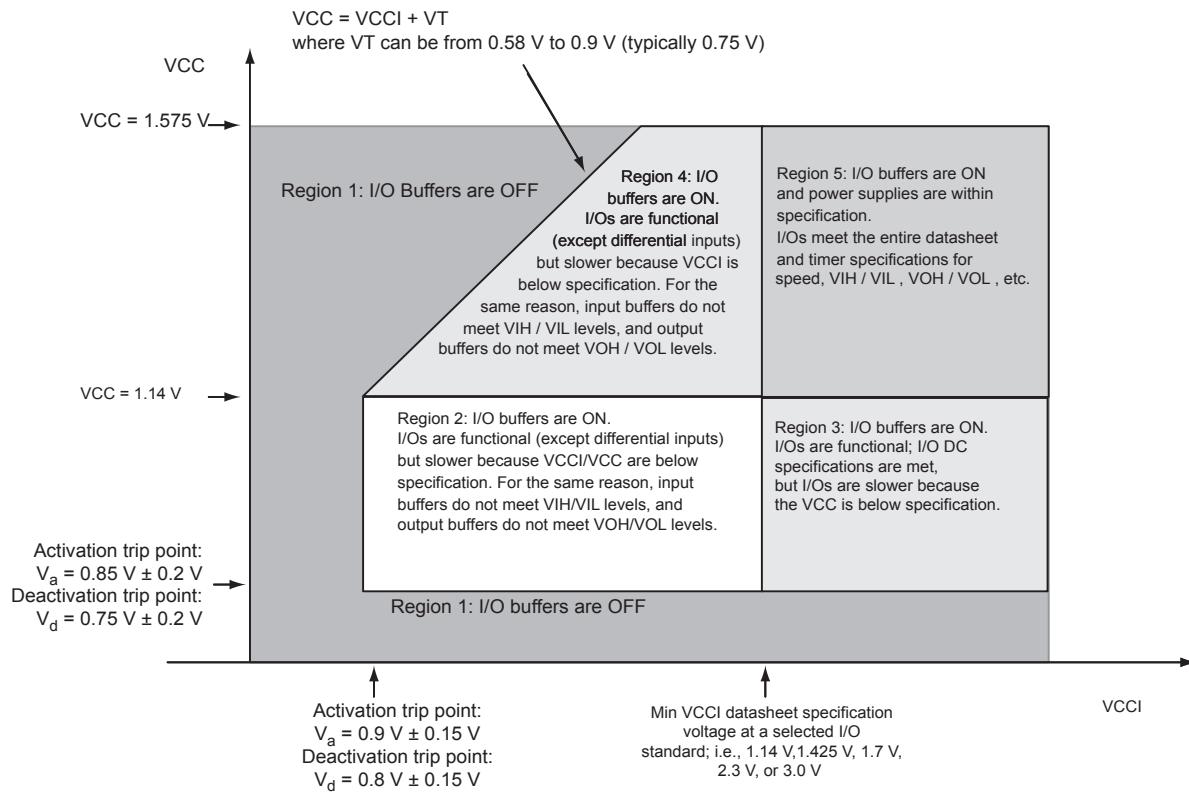


Figure 2-2 • Device Operating at 1.2 V Core Voltage – I/O State as a Function of VCCI and VCC Voltage Levels; Only A3PE600L and A3PE3000L Devices Operate at 1.2 V Core Voltage

Thermal Characteristics

Introduction

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because dynamic and static power consumption cause the chip junction temperature to be higher than the ambient temperature.

EQ 1 can be used to calculate junction temperature.

$$T_J = \text{Junction Temperature} = \Delta T + T_A \quad \text{EQ 1}$$

where:

T_A = Ambient Temperature

ΔT = Temperature gradient between junction (silicon) and ambient $\Delta T = \theta_{ja} * P$

θ_{ja} = Junction-to-ambient of the package. θ_{ja} numbers are located in Table 2-5.

P = Power dissipation

Package Thermal Characteristics

The device junction-to-case thermal resistivity is θ_{jc} and the junction-to-ambient air thermal resistivity is θ_{ja} . The thermal characteristics for θ_{ja} are shown for two air flow rates. The recommended maximum junction temperature is 125°C. EQ 2 shows a sample calculation of the recommended maximum power dissipation allowed for a 484-pin FBGA package at military temperature and in still air.

$$\text{Maximum Power Allowed} = \frac{\text{Max. junction temp. } (\text{°C}) - \text{Max. ambient temp. } (\text{°C})}{\theta_{ja} (\text{°C/W})} = \frac{125^\circ\text{C} - 70^\circ\text{C}}{20.6^\circ\text{C/W}} = 2.670$$

**Table 2-15 • Summary of I/O Input Buffer Power (per pin) – Default I/O Software Settings
Applicable to Advanced I/O Banks for A3P250 and A3P1000 Only**

	VMV (V)	Static Power PDC6 (mW) ¹	Dynamic Power PAC9 (μ W/MHz) ²
Single-Ended			
3.3 V LVTTL / 3.3 V LVC MOS	3.3	–	16.22
3.3 V LVC MOS – Wide Range	3.3	–	16.22
2.5 V LVC MOS	2.5	–	4.65
1.8 V LVC MOS	1.8	–	1.65
1.5 V LVC MOS (JESD8-11)	1.5	–	0.98
3.3 V PCI	3.3	–	17.64
3.3 V PCI-X	3.3	–	17.64
Differential			
LVDS	2.5	2.26	0.83
LVPECL	3.3	5.72	1.81

Notes:

1. PDC6 is the static power (where applicable) measured on VMV.
2. PAC9 is the total dynamic power measured on VMV.

**Table 2-16 • Summary of I/O Input Buffer Power (per pin) – Default I/O Software Settings
Applicable to Standard Plus I/O Banks for A3P250 and A3P1000 Only**

	VMV (V)	Static Power PDC6 (mW) ¹	Dynamic Power PAC9 (μ W/MHz) ²
Single-Ended			
3.3 V LVTTL / 3.3 V LVC MOS	3.3	–	16.23
3.3 V LVC MOS – Wide Range	3.3	–	16.23
2.5 V LVC MOS	2.5	–	4.66
1.8 V LVC MOS	1.8	–	1.64
1.5 V LVC MOS (JESD8-11)	1.5	–	0.99
3.3 V PCI	3.3	–	17.64
3.3 V PCI-X	3.3	–	17.64

Notes:

1. PDC6 is the static power (where applicable) measured on VMV.
2. PAC9 is the total dynamic power measured on VMV.

Table 2-18 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings¹
Applicable to Advanced I/O Banks for A3P250 and A3P1000 Only

	C _{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μW/MHz) ³
Single-Ended				
3.3 V LVTTL / 3.3 V LVCMOS	5	3.3	–	141.97
3.3 V LVCMOS Wide Range	5	3.3	–	141.97
2.5 V LVCMOS	5	2.5	–	79.98
1.8 V LVCMOS	5	1.8	–	52.26
1.5 V LVCMOS (JESD8-11)	5	1.5	–	35.62
3.3 V PCI	10	3.3	–	201.02
3.3 V PCI-X	10	3.3	–	201.02
Differential				
LVDS	–	2.5	7.74	89.82
LVPECL	–	3.3	19.54	167.55

Notes:

1. Dynamic Power consumption is given for software default drive strength and output slew. Output load is lower than the software default.
2. PDC7 is the static power (where applicable) measured on VCCI.
3. PAC10 is the total dynamic power measured on VCCI.

Table 2-19 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings
Applicable to Standard Plus I/O Banks for A3P250 and A3P1000 Only

	C _{LOAD} (pF)	VCCI (V)	Static Power PDC7 (mW) ²	Dynamic Power PAC10 (μW/MHz) ³
Single-Ended				
3.3 V LVTTL / 3.3 V LVCMOS	5	3.3	–	125.97
3.3 V LVCMOS – Wide Range	5	3.3	–	125.97
2.5 V LVCMOS	5	2.5	–	70.82
1.8 V LVCMOS	5	1.8	–	36.39
1.5 V LVCMOS (JESD8-11)	5	1.5	–	25.34
3.3 V PCI	10	3.3	–	184.92
3.3 V PCI-X	10	3.3	–	184.92

Notes:

1. Dynamic Power consumption is given for software default drive strength and output slew. Output load is lower than the software default.
2. PDC7 is the static power (where applicable) measured on VCCI.
3. PAC10 is the total dynamic power measured on VCCI.

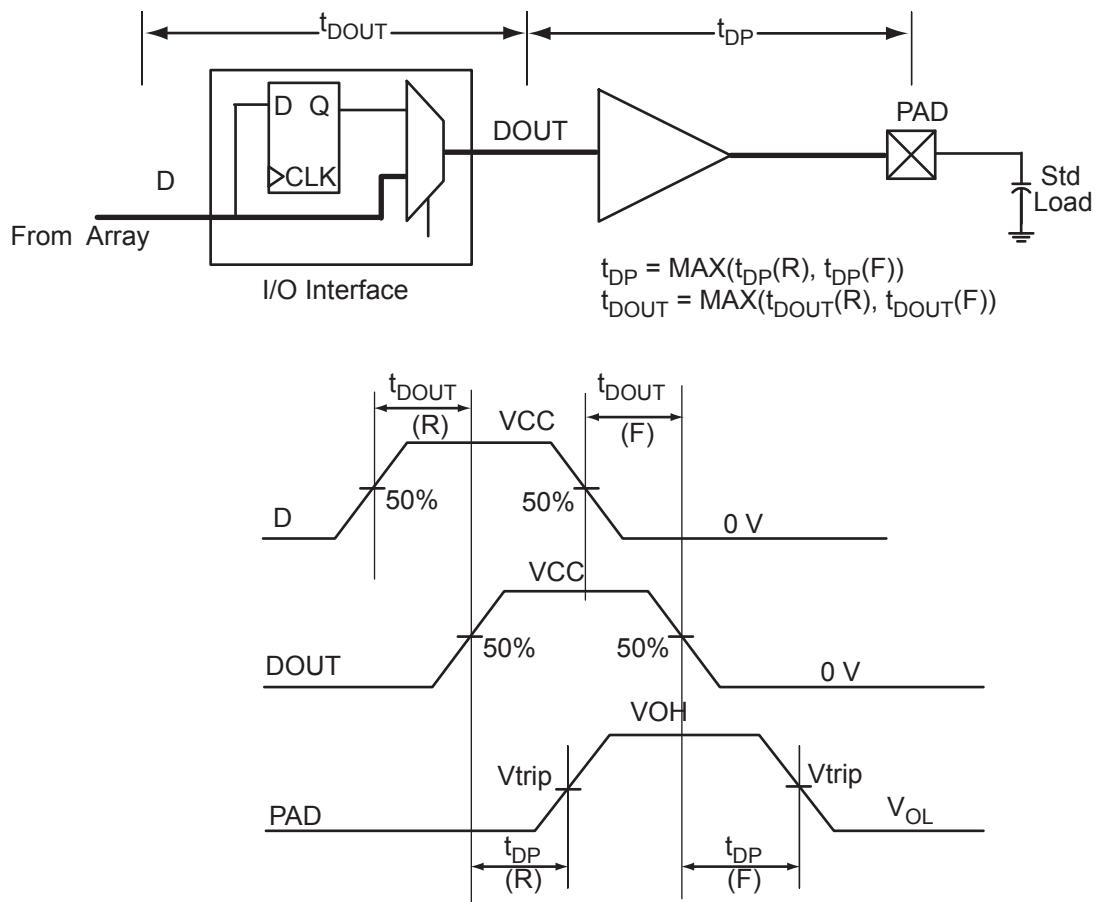


Figure 2-5 • Output Buffer Model and Delays (example)

Table 2-33 • Summary of I/O Timing Characteristics—Software Default Settings–1 Speed Grade, Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst Case VCC = 1.425 V,

Worst Case VCCI

Applicable to Advanced I/O Banks for A3P250 and A3P1000 Only

I/O Standard	Drive Strength (mA)	Equivalent Software Default Drive Strength Option ¹	Slew Rate	Capacitive Load (pF) ²	External Resistor (Ω)	t_{DOUT} (ns)	t_{DP} (ns)	t_{DIN} (ns)	t_{PY} (ns)	t_{EOUT} (ns)	t_{ZL} (ns)	t_{ZH} (ns)	t_{LZ} (ns)	t_{HZ} (ns)	t_{ZLS} (ns)	t_{ZHS} (ns)
3.3 V LVTTL / 3.3 V LVCMOS	12 mA	12 mA	High	5	–	0.54	2.24	0.04	0.95	0.39	2.28	1.70	3.00	3.35	4.38	3.79
3.3 V LVCMOS Wide Range ³	100 μ A	12 mA	High	5	–	0.54	3.47	0.04	1.44	0.39	3.47	2.57	4.65	5.18	6.64	5.75
2.5 V LVCMOS	12 mA	12 mA	High	5	–	0.54	2.26	0.04	1.23	0.39	2.30	1.89	3.09	3.22	4.39	3.99
1.8 V LVCMOS	12 mA	12 mA	High	5	–	0.54	2.49	0.04	1.14	0.39	2.54	2.12	3.46	3.82	4.63	4.21
1.5 V LVCMOS	12 mA	12 mA	High	5	–	0.54	2.85	0.04	1.35	0.39	2.90	2.45	3.69	3.93	4.99	4.55
3.3 V PCI	Per PCI spec.		High	10	25 ⁴	0.54	2.51	0.04	0.81	0.39	2.55	1.83	3.00	3.35	4.65	3.92
3.3 V PCI-X	Per PCI-X spec.		High	10	25 ⁴	0.54	2.51	0.04	0.78	0.39	2.55	1.83	3.00	3.35	4.65	3.92
LVDS	24 mA		High	–	–	0.54	1.76	0.04	1.55	–	–	–	–	–	–	–
LVPECL	24 mA		High	–	–	0.54	1.68	0.04	1.31	–	–	–	–	–	–	–

Notes:

1. Note that 3.3 V LVCMOS wide range is applicable to 100 μ A drive strength only. The configuration will not operate at the equivalent software default drive strength. These values are for normal ranges only.
2. Output delays provided in this table were extracted with an output load indicated in the Capacitive Load column. For a specific output load, refer to Designer software. Software default load is higher.
3. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD8-B specification.
4. Resistance is used to measure I/O propagation delays as defined in PCI specifications. See [Figure 2-14 on page 2-71](#) for connectivity. This resistor is not required during normal operation.
5. For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Table 2-54 • 3.3 V LVTTL / 3.3 V LVC MOS Low Slew

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V
Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
4 mA	Std.	0.63	6.25	0.05	1.12	0.45	6.37	5.29	2.91	2.70	8.83	7.75	ns
	-1	0.54	5.32	0.04	0.95	0.39	5.42	4.50	2.47	2.30	7.51	6.59	ns
6 mA	Std.	0.63	5.25	0.05	1.12	0.45	5.35	4.58	3.28	3.34	7.81	7.04	ns
	-1	0.54	4.47	0.04	0.95	0.39	4.55	3.90	2.79	2.85	6.65	5.99	ns
8 mA	Std.	0.63	5.25	0.05	1.12	0.45	5.35	4.58	3.28	3.34	7.81	7.04	ns
	-1	0.54	4.47	0.04	0.95	0.39	4.55	3.90	2.79	2.85	6.65	5.99	ns
12 mA	Std.	0.63	4.50	0.05	1.12	0.45	4.59	4.05	3.53	3.76	7.05	6.51	ns
	-1	0.54	3.83	0.04	0.95	0.39	3.90	3.45	3.00	3.20	5.99	5.54	ns
16 mA	Std.	0.63	4.27	0.05	1.12	0.45	4.35	3.93	3.58	3.86	6.81	6.39	ns
	-1	0.54	3.63	0.04	0.95	0.39	3.70	3.34	3.05	3.29	5.79	5.43	ns
24 mA	Std.	0.63	4.14	0.05	1.12	0.45	4.22	3.97	3.65	4.27	6.68	6.43	ns
	-1	0.54	3.53	0.04	0.95	0.39	3.59	3.38	3.10	3.63	5.68	5.47	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Table 2-55 • 3.3 V LVTTL / 3.3 V LVC MOS High Slew

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V
Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
4 mA	Std.	0.63	3.55	0.05	1.12	0.45	3.62	2.79	2.91	2.87	6.07	5.25	ns
	-1	0.54	3.02	0.04	0.95	0.39	3.08	2.37	2.48	2.44	5.17	4.46	ns
6 mA	Std.	0.63	2.95	0.05	1.12	0.45	3.00	2.25	3.28	3.52	5.46	4.71	ns
	-1	0.54	2.51	0.04	0.95	0.39	2.55	1.91	2.79	3.00	4.65	4.01	ns
8 mA	Std.	0.63	2.95	0.05	1.12	0.45	3.00	2.25	3.28	3.52	5.46	4.71	ns
	-1	0.54	2.51	0.04	0.95	0.39	2.55	1.91	2.79	3.00	4.65	4.01	ns
12 mA	Std.	0.63	2.64	0.05	1.12	0.45	2.68	1.99	3.53	3.94	5.14	4.45	ns
	-1	0.54	2.24	0.04	0.95	0.39	2.28	1.70	3.00	3.35	4.38	3.79	ns
16 mA	Std.	0.63	2.58	0.05	1.12	0.45	2.63	1.95	3.59	4.05	5.09	4.41	ns
	-1	0.54	2.20	0.04	0.95	0.39	2.24	1.66	3.05	3.44	4.33	3.75	ns
24 mA	Std.	0.63	2.61	0.05	1.12	0.45	2.66	1.89	3.66	4.46	5.12	4.35	ns
	-1	0.54	2.22	0.04	0.95	0.39	2.26	1.61	3.11	3.80	4.35	3.70	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Table 2-66 • 3.3 V LVC MOS Wide Range Low SlewMilitary-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.7 V

Applicable to Advanced I/O Banks

Drive Strength	Equiv. Software Default Drive Strength Option ¹	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
100 μA	4 mA	Std.	0.63	9.67	0.05	1.70	0.45	9.67	8.03	4.50	4.18	13.40	11.77	ns
		-1	0.54	8.22	0.04	1.44	0.39	8.22	6.83	3.83	3.55	11.40	10.01	ns
100 μA	6mA	Std.	0.63	8.13	0.05	1.70	0.45	8.13	6.95	5.07	5.17	11.86	10.69	ns
		-1	0.54	6.91	0.04	1.44	0.39	6.91	5.92	4.31	4.40	10.09	9.09	ns
100 μA	8 mA	Std.	0.63	8.13	0.05	1.70	0.45	8.13	6.95	5.07	5.17	11.86	10.69	ns
		-1	0.54	6.91	0.04	1.44	0.39	6.91	5.92	4.31	4.40	10.09	9.09	ns
100 μA	12 mA	Std.	0.63	6.96	0.05	1.70	0.45	6.96	6.15	5.45	5.81	10.70	9.89	ns
		-1	0.54	5.92	0.04	1.44	0.39	5.92	5.24	4.64	4.94	9.10	8.41	ns
100 μA	16 mA	Std.	0.63	6.61	0.05	1.70	0.45	6.61	5.96	5.54	5.97	10.34	9.70	ns
		-1	0.54	5.62	0.04	1.44	0.39	5.62	5.07	4.71	5.08	8.80	8.25	ns

Notes:

1. Note that 3.3 V LVC MOS wide range is applicable to 100 μA drive strength only. The configuration will not operate at the equivalent software default drive strength. These values are for normal ranges ONLY.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-67 • 3.3 V LVC MOS Wide Range High SlewMilitary-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.7 V

Applicable to Advanced I/O Banks

Drive Strength	Equiv. Software Default Drive Strength Option ¹	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
100 μA	4 mA	Std.	0.63	5.49	0.05	1.70	0.45	5.49	4.23	4.51	4.44	9.22	7.97	ns
		-1	0.54	4.67	0.04	1.44	0.39	4.57	3.60	3.83	3.78	7.84	6.78	ns
100 μA	6 mA	Std.	0.63	4.56	0.05	1.70	0.45	4.56	3.42	5.08	5.45	8.29	7.15	ns
		-1	0.54	3.88	0.04	1.44	0.39	3.88	2.91	4.32	4.64	7.05	6.08	ns
100 μA	8 mA	Std.	0.63	4.56	0.05	1.70	0.45	4.56	3.42	5.08	5.45	8.29	7.15	ns
		-1	0.54	3.88	0.04	1.44	0.39	3.88	2.91	4.32	4.64	7.05	6.08	ns
100 μA	12 mA	Std.	0.63	4.08	0.05	1.70	0.45	4.08	3.03	5.46	6.09	7.81	6.76	ns
		-1	0.54	3.47	0.04	1.44	0.39	3.47	2.57	4.65	5.18	6.64	5.75	ns
100 μA	16 mA	Std.	0.63	4.00	0.05	1.70	0.45	4.00	2.96	5.55	6.26	7.73	6.69	ns
		-1	0.54	3.40	0.04	1.44	0.39	3.40	2.51	4.72	5.32	6.58	5.69	ns

Notes:

1. Note that 3.3 V LVC MOS wide range is applicable to 100 μA drive strength only. The configuration will not operate at the equivalent software default drive strength. These values are for normal ranges only.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

1.2 V LVCMOS (JESD8-12A)

Low-Voltage CMOS for 1.2 V complies with the LVCMOS standard JESD8-12A for general purpose 1.2 V applications. It uses a 1.2 V input buffer and a push-pull output buffer.

**Table 2-106 • Minimum and Maximum DC Input and Output Levels
Applicable to Pro I/O Banks for A3PE600L and A3PE3000L Only**

1.2 V LVCMOS ¹	VIL		VIH		VOL	VOH	I _{OL}	I _{OH}	I _{OSH}	I _{OSL}	I _{IL} ²	I _{IH} ³
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. ⁴ mA	Max. ⁴ mA	μA ⁵	μA ⁵
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	2	2	TBD	TBD	15	15

Notes:

1. Applicable to A3PE600L and A3PE3000L devices only.
2. I_{IL} is the input leakage current per I/O pin over recommended operation conditions where $-0.3 \text{ V} < V_{IN} < V_{IL}$.
3. I_{IH} is the input leakage current per I/O pin over recommended operating conditions $V_{IH} < V_{IN} < V_{CCI}$. Input current is larger when operating outside recommended ranges
4. Currents are measured at 100°C junction temperature and maximum voltage.
5. Currents are measured at 125°C junction temperature.
6. Software default selection highlighted in gray.

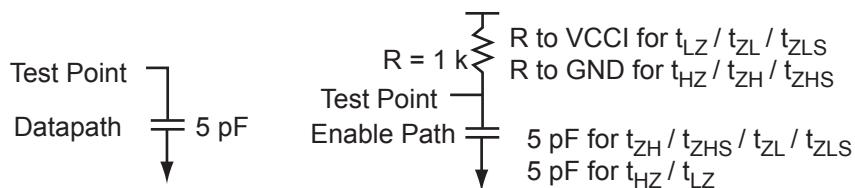


Figure 2-12 • AC Loading

Table 2-107 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (Typ) (V)	C _{LOAD} (pF)
0	1.2	0.6	-	5

Note: *Measuring point = V_{trip} . See Table 2-29 on page 2-25 for a complete table of trip points.

2.5 V GTL+

Gunning Transceiver Logic Plus is a high-speed bus standard (JESD8-3). It provides a differential amplifier input buffer and an open-drain output buffer. The V_{CCI} pin should be connected to 2.5 V.

Table 2-132 • Minimum and Maximum DC Input and Output Levels

2.5 V GTL+	VIL		VIH		VOL	VOH	I _{OL}	I _{OH}	I _{OSL}	I _{OSH}	I _{IL} ¹	I _{IH} ²
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ³	Max. mA ³	μA ⁴	μA ⁴
33 mA	-0.3	VREF - 0.1	VREF + 0.1	3.6	0.6	-	33	33	169	124	15	15

Notes:

1. I_{IL} is the input leakage current per I/O pin over recommended operating conditions where $-0.3 \text{ V} < \text{VIN} < \text{VIL}$.
2. I_{IH} is the input leakage current per I/O pin over recommended operating conditions $\text{VIH} < \text{VIN} < \text{VCCI}$. Input current is larger when operating outside recommended ranges.
3. Currents are measured at 100°C junction temperature and maximum voltage.
4. Currents are measured at 125°C junction temperature.

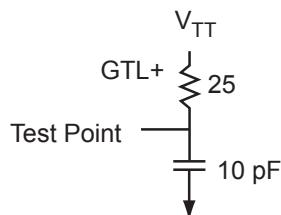


Figure 2-18 • AC Loading

Table 2-133 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF - 0.1	VREF + 0.1	1.0	1.0	1.5	10

Note: *Measuring point = V_{trip} . See Table 2-29 on page 2-25 for a complete table of trip points.

Timing Characteristics

Table 2-134 • 2.5 V GTL+

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.14 V,

Worst-Case VCCI = 2.3 V, VREF = 1.0 V

Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.80	2.19	0.05	2.27	0.52	2.22	2.08	—	—	4.43	4.28	ns
-1	0.68	1.86	0.05	1.93	0.44	1.89	1.77	—	—	3.77	3.64	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Table 2-135 • 2.5 V GTL+

Military-Case Conditions: $T_J = 125^\circ\text{C}$, VCC = 1.425 V,

Worst-Case VCCI = 2.3 V, VREF = 1.0 V

Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.61	2.05	0.04	2.04	0.40	2.07	1.99	—	—	3.53	3.46	ns
-1	0.52	1.75	0.03	1.73	0.34	1.76	1.69	—	—	3.00	2.94	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

Timing Characteristics

1.2 V DC Core Voltage

Table 2-162 • LVDS

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 2.3 V
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.80	1.87	0.05	2.48	ns
-1	0.68	1.59	0.05	2.11	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

1.5 V DC Core Voltage

Table 2-163 • LVDS

Military-Case Conditions: $T_J = 125^\circ\text{C}$, VCC = 1.425 V, Worst-Case VCCI = 2.3 V
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.61	1.75	0.04	2.18	ns
-1	0.52	1.48	0.03	1.86	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-164 • LVDS

Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 2.3 V
Applicable to Advanced I/O Banks for A3P250 and A3P1000 Only

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.63	2.07	0.05	1.82	ns
-1	0.54	1.76	0.04	1.55	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Timing Characteristics

1.2 V DC Core Voltage

Table 2-167 • LVPECL

**Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.14 V, Worst-Case VCCI = 3.0 V
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only**

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.80	1.78	0.05	2.16	ns
-1	0.68	1.51	0.05	1.84	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

1.5 V DC Core Voltage

Table 2-168 • LVPECL

**Military-Case Conditions: $T_J = 125^\circ\text{C}$, VCC = 1.425 V, Worst-Case VCCI = 3.0 V
Applicable to Pro I/Os for A3PE600L and A3PE3000L Only**

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.61	1.65	0.04	1.89	ns
-1	0.52	1.40	0.03	1.61	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

Table 2-169 • LVPECL

**Military-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V
Applicable to Advanced I/O Banks for A3P250 and A3P1000 Only**

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.63	1.98	0.05	1.54	ns
-1	0.54	1.68	0.04	1.31	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Table 2-174 • Input Data Register Propagation DelaysMilitary-Case Conditions: $T_J = 125^\circ\text{C}$, Worst-Case VCC = 1.425 V for A3P250 and A3P1000

Parameter	Description	-1	Std.	Units
t_{ICLKQ}	Clock-to-Q of the Input Data Register	0.29	0.34	ns
t_{ISUD}	Data Setup Time for the Input Data Register	0.32	0.37	ns
t_{IHD}	Data Hold Time for the Input Data Register	0.00	0.00	ns
t_{ISUE}	Enable Setup Time for the Input Data Register	0.45	0.53	ns
t_{IHE}	Enable Hold Time for the Input Data Register	0.00	0.00	ns
t_{ICLR2Q}	Asynchronous Clear-to-Q of the Input Data Register	0.55	0.64	ns
t_{IPRE2Q}	Asynchronous Preset-to-Q of the Input Data Register	0.55	0.64	ns
t_{IREMCLR}	Asynchronous Clear Removal Time for the Input Data Register	0.00	0.00	ns
t_{IRECCLR}	Asynchronous Clear Recovery Time for the Input Data Register	0.27	0.31	ns
t_{IREMPRE}	Asynchronous Preset Removal Time for the Input Data Register	0.00	0.00	ns
t_{IRECPRE}	Asynchronous Preset Recovery Time for the Input Data Register	0.27	0.31	ns
t_{IWCLR}	Asynchronous Clear Minimum Pulse Width for the Input Data Register	0.25	0.30	ns
t_{WPRE}	Asynchronous Preset Minimum Pulse Width for the Input Data Register	0.25	0.30	ns
t_{CKMPWH}	Clock Minimum Pulse Width HIGH for the Input Data Register	0.41	0.48	ns
t_{CKMPWL}	Clock Minimum Pulse Width LOW for the Input Data Register	0.37	0.43	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-7 on page 2-6](#) for derating values.

Output DDR Module

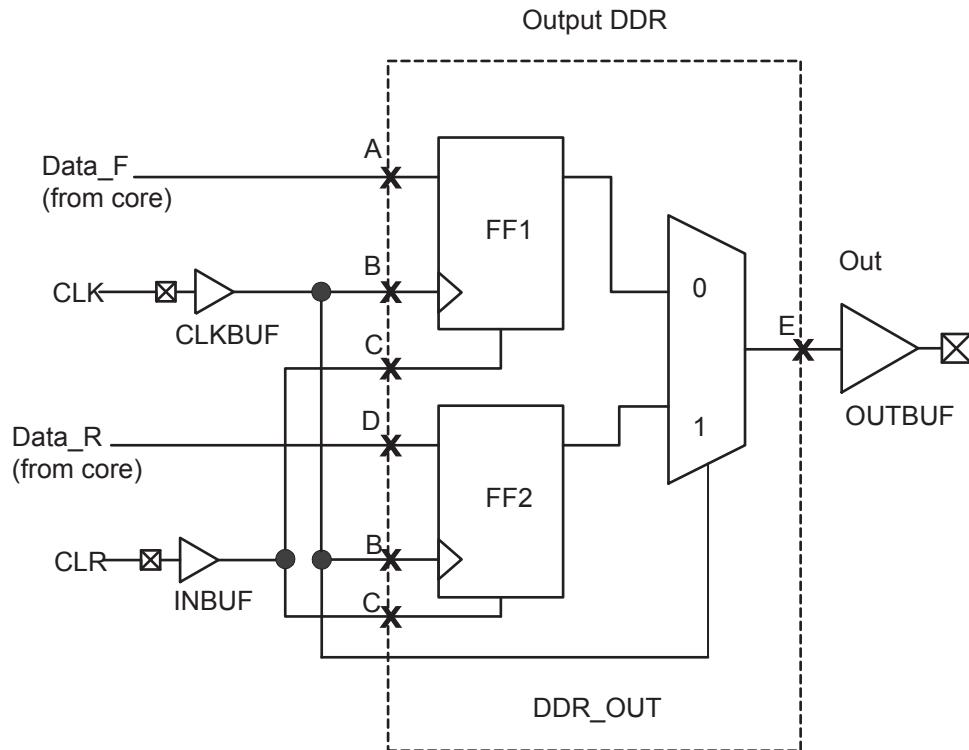


Figure 2-35 • Output DDR Timing Model

Table 2-185 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
$t_{DDROCLKQ}$	Clock-to-Out	B, E
$t_{DDROCLR2Q}$	Asynchronous Clear-to-Out	C, E
$t_{DDROREMCLR}$	Clear Removal	C, B
$t_{DDRORECCR}$	Clear Recovery	C, B
$t_{DDROSUD1}$	Data Setup Data_F	A, B
$t_{DDROSUD2}$	Data Setup Data_R	D, B
$t_{DDROHD1}$	Data Hold Data_F	A, B
$t_{DDROHD2}$	Data Hold Data_R	D, B

Table 2-193 • Register DelaysMilitary-Case Conditions: $T_J = 125^\circ\text{C}$, $V_{CC} = 1.425 \text{ V}$ for A3PE600L and A3PE3000L

Parameter	Description	-1	Std.	Units
t_{CLKQ}	Clock-to-Q of the Core Register	0.58	0.69	ns
t_{SUD}	Data Setup Time for the Core Register	0.45	0.53	ns
t_{HD}	Data Hold Time for the Core Register	0.00	0.00	ns
t_{SUE}	Enable Setup Time for the Core Register	0.48	0.57	ns
t_{HE}	Enable Hold Time for the Core Register	0.00	0.00	ns
t_{CLR2Q}	Asynchronous Clear-to-Q of the Core Register	0.42	0.50	ns
t_{PRE2Q}	Asynchronous Preset-to-Q of the Core Register	0.42	0.50	ns
t_{REMCLR}	Asynchronous Clear Removal Time for the Core Register	0.00	0.00	ns
t_{RECCR}	Asynchronous Clear Recovery Time for the Core Register	0.24	0.28	ns
t_{REMPRE}	Asynchronous Preset Removal Time for the Core Register	0.00	0.00	ns
t_{RECPRE}	Asynchronous Preset Recovery Time for the Core Register	0.24	0.28	ns
t_{WCLR}	Asynchronous Clear Minimum Pulse Width for the Core Register	0.30	0.34	ns
t_{WPRE}	Asynchronous Preset Minimum Pulse Width for the Core Register	0.30	0.34	ns
t_{CKMPWH}	Clock Minimum Pulse Width HIGH for the Core Register	0.56	0.64	ns
t_{CKMPWL}	Clock Minimum Pulse Width LOW for the Core Register	0.56	0.64	ns

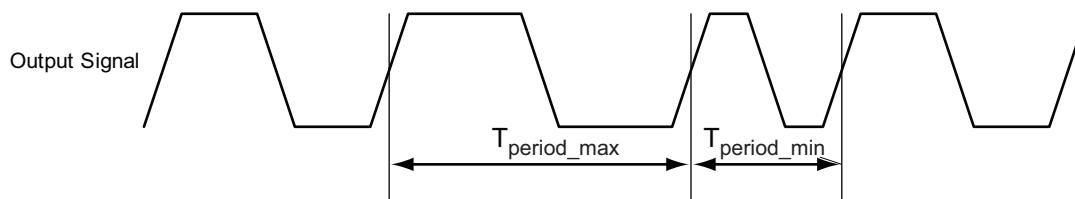
Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.

**Table 2-202 • Military ProASIC3/EL CCC/PLL Specification
For Devices Operating at 1.5 V DC Core Voltage**

Parameter	Min.	Typ.	Max.	Units
Clock Conditioning Circuitry Input Frequency f_{IN_CCC}	1.5		350	MHz
Clock Conditioning Circuitry Output Frequency f_{OUT_CCC}	0.75		350	MHz
Delay Increments in Programmable Delay Blocks ^{1, 2,3}		160		ps
Number of Programmable Values in Each Programmable Delay Block			32	
Serial Clock (SCLK) for Dynamic PLL ⁴			110	MHz
Input cycle-to-cycle jitter (peak magnitude)			1.5	ns
Acquisition Time				
LockControl = 0			300	μs
LockControl = 1			6.0	ms
Tracking Jitter ⁵				
LockControl = 0			1.6	ns
LockControl = 1			0.8	ns
Output Duty Cycle	48.5		51.5	%
Delay Range in Block: Programmable Delay 1 ^{1,2}	0.6		5.56	ns
Delay Range in Block: Programmable Delay 2 ^{1,2}	0.025		5.56	ns
Delay Range in Block: Fixed Delay ^{1,2}		2.2		ns
CCC Output Peak-to-Peak Period Jitter F_{CCC_OUT}	Max. Peak-to-Peak Period Jitter ^{6,7}			
	SSO ≤ 2	SSO ≤ 4	SSO ≤ 8	SSO ≤ 16
0.75 MHz to 50 MHz	0.50%	0.50%	0.70%	1.00%
50 MHz to 250 MHz	1.00%	3.00%	5.00%	9.00%
250 MHz to 350 MHz	2.50%	4.00%	6.00%	12.00%

Notes:

1. This delay is a function of voltage and temperature. See [Table 2-6 on page 2-6](#) for deratings.
2. $T_J = 25^\circ\text{C}$, $VCC = 1.5 \text{ V}$.
3. When the CCC/PLL core is generated by Microsemi core generator software, not all delay values of the specified delay increments are available. Refer to the [Libero online help](#) associated with the core for more information.
4. Maximum value obtained for a -1 speed grade device in worst-case military conditions. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-6](#) for derating values.
5. Tracking jitter is defined as the variation in clock edge position of PLL outputs with reference to PLL input clock edge. Tracking jitter does not measure the variation in PLL output period, which is covered by period jitter parameter.
6. Measurements done with LVTTL 3.3 V, 8 mA I/O drive strength and high slew rate. $VCC/VCCPLL = 1.425 \text{ V}$, VQ/PQ/TQ type of packages, 20 pF load.
7. Switching I/Os are placed outside of the PLL bank.



Note: Peak-to-peak jitter measurements are defined by $T_{peak-to-peak} = T_{period_max} - T_{period_min}$.

Figure 2-42 • Peak-to-Peak Jitter Definition

Embedded SRAM and FIFO Characteristics

SRAM

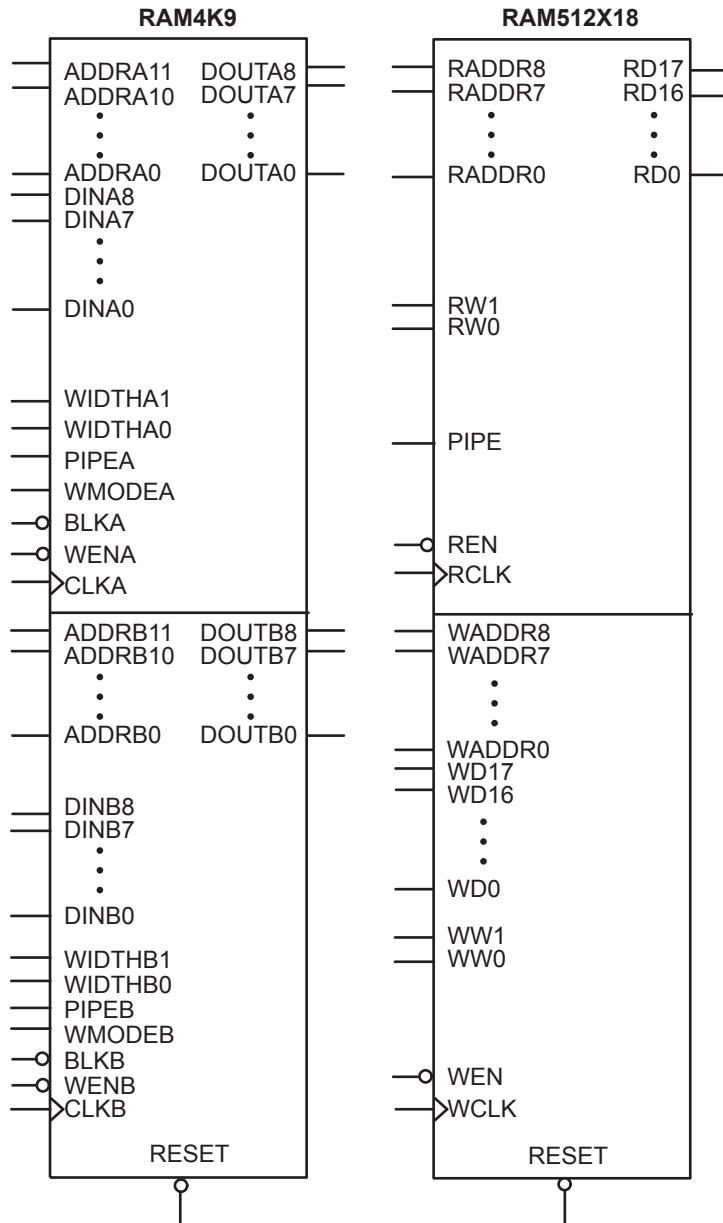


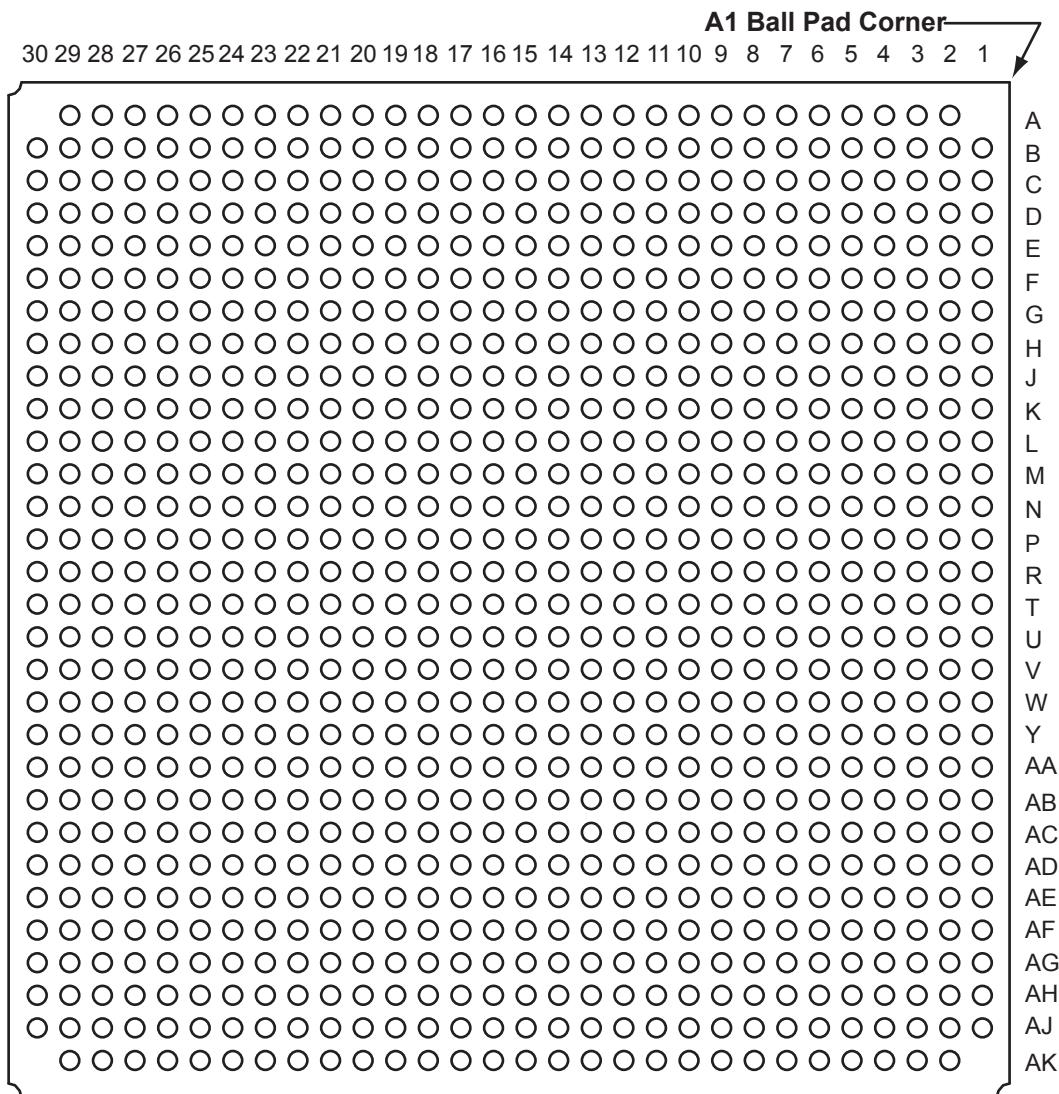
Figure 2-43 • RAM Models

FG256	
Pin Number	A3P1000 Function
A1	GND
A2	GAA0/IO00RSB0
A3	GAA1/IO01RSB0
A4	GAB0/IO02RSB0
A5	IO16RSB0
A6	IO22RSB0
A7	IO28RSB0
A8	IO35RSB0
A9	IO45RSB0
A10	IO50RSB0
A11	IO55RSB0
A12	IO61RSB0
A13	GBB1/IO75RSB0
A14	GBA0/IO76RSB0
A15	GBA1/IO77RSB0
A16	GND
B1	GAB2/IO224PDB3
B2	GAA2/IO225PDB3
B3	GNDQ
B4	GAB1/IO03RSB0
B5	IO17RSB0
B6	IO21RSB0
B7	IO27RSB0
B8	IO34RSB0
B9	IO44RSB0
B10	IO51RSB0
B11	IO57RSB0
B12	GBC1/IO73RSB0
B13	GBB0/IO74RSB0
B14	IO71RSB0
B15	GBA2/IO78PDB1
B16	IO81PDB1
C1	IO224NDB3
C2	IO225NDB3
C3	VMV3
C4	IO11RSB0
C5	GAC0/IO04RSB0
C6	GAC1/IO05RSB0

FG256	
Pin Number	A3P1000 Function
C7	IO25RSB0
C8	IO36RSB0
C9	IO42RSB0
C10	IO49RSB0
C11	IO56RSB0
C12	GBC0/IO72RSB0
C13	IO62RSB0
C14	VMV0
C15	IO78NDB1
C16	IO81NDB1
D1	IO222NDB3
D2	IO222PDB3
D3	GAC2/IO223PDB3
D4	IO223NDB3
D5	GNDQ
D6	IO23RSB0
D7	IO29RSB0
D8	IO33RSB0
D9	IO46RSB0
D10	IO52RSB0
D11	IO60RSB0
D12	GNDQ
D13	IO80NDB1
D14	GBB2/IO79PDB1
D15	IO79NDB1
D16	IO82NSB1
E1	IO217PDB3
E2	IO218PDB3
E3	IO221NDB3
E4	IO221PDB3
E5	VMV0
E6	VCCIB0
E7	VCCIB0
E8	IO38RSB0
E9	IO47RSB0
E10	VCCIB0
E11	VCCIB0
E12	VMV1

FG256	
Pin Number	A3P1000 Function
E13	GBC2/IO80PDB1
E14	IO83PPB1
E15	IO86PPB1
E16	IO87PDB1
F1	IO217NDB3
F2	IO218NDB3
F3	IO216PDB3
F4	IO216NDB3
F5	VCCIB3
F6	GND
F7	VCC
F8	VCC
F9	VCC
F10	VCC
F11	GND
F12	VCCIB1
F13	IO83NPB1
F14	IO86NPB1
F15	IO90PPB1
F16	IO87NDB1
G1	IO210PSB3
G2	IO213NDB3
G3	IO213PDB3
G4	GFC1/IO209PPB3
G5	VCCIB3
G6	VCC
G7	GND
G8	GND
G9	GND
G10	GND
G11	VCC
G12	VCCIB1
G13	GCC1/IO91PPB1
G14	IO90NPB1
G15	IO88PDB1
G16	IO88NDB1
H1	GFB0/IO208NPB3
H2	GFA0/IO207NDB3

FG896



Note: This is the bottom view.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at
<http://www.microsemi.com/products/fpga-soc/solutions>.

FG896	
Pin Number	A3PE3000L Function
AG5	IO220PPB5V3
AG6	IO228PDB5V4
AG7	IO231NDB5V4
AG8	GEC2/IO231PDB5V4
AG9	IO225NPB5V3
AG10	IO223NPB5V3
AG11	IO221PDB5V3
AG12	IO221NDB5V3
AG13	IO205NPB5V1
AG14	IO199NDB5V0
AG15	IO199PDB5V0
AG16	IO187NDB4V4
AG17	IO187PDB4V4
AG18	IO181NDB4V3
AG19	IO171PPB4V2
AG20	IO165NPB4V1
AG21	IO161NPB4V0
AG22	IO159NDB4V0
AG23	IO159PDB4V0
AG24	IO158PPB4V0
AG25	GDB2/IO155PDB4V0
AG26	GDA2/IO154PPB4V0
AG27	GND
AG28	VJTAG
AG29	VCC
AG30	IO149NDB3V4
AH1	GND
AH2	IO233NPB5V4
AH3	VCC
AH4	FF/GEB2/IO232PPB5V4
AH5	VCCIB5
AH6	IO219NDB5V3
AH7	IO219PDB5V3
AH8	IO227NDB5V4
AH9	IO227PDB5V4

FG896	
Pin Number	A3PE3000L Function
AH10	IO225PPB5V3
AH11	IO223PPB5V3
AH12	IO211NDB5V2
AH13	IO211PDB5V2
AH14	IO205PPB5V1
AH15	IO195NDB5V0
AH16	IO185NDB4V3
AH17	IO185PDB4V3
AH18	IO181PDB4V3
AH19	IO177NDB4V2
AH20	IO171NPB4V2
AH21	IO165PPB4V1
AH22	IO161PPB4V0
AH23	IO157NDB4V0
AH24	IO157PDB4V0
AH25	IO155NDB4V0
AH26	VCCIB4
AH27	TDI
AH28	VCC
AH29	VPUMP
AH30	GND
AJ1	GND
AJ2	GND
AJ3	GEA2/IO233PPB5V4
AJ4	VCC
AJ5	IO217NPB5V2
AJ6	VCC
AJ7	IO215NPB5V2
AJ8	IO213NDB5V2
AJ9	IO213PDB5V2
AJ10	IO209NDB5V1
AJ11	IO209PDB5V1
AJ12	IO203NDB5V1
AJ13	IO203PDB5V1
AJ14	IO197NDB5V0
AJ15	IO195PDB5V0

FG896	
Pin Number	A3PE3000L Function
AJ16	IO183NDB4V3
AJ17	IO183PDB4V3
AJ18	IO179NPB4V3
AJ19	IO177PDB4V2
AJ20	IO173NDB4V2
AJ21	IO173PDB4V2
AJ22	IO163NDB4V1
AJ23	IO163PDB4V1
AJ24	IO167NPB4V1
AJ25	VCC
AJ26	IO156NPB4V0
AJ27	VCC
AJ28	TMS
AJ29	GND
AJ30	GND
AK2	GND
AK3	GND
AK4	IO217PPB5V2
AK5	GND
AK6	IO215PPB5V2
AK7	GND
AK8	IO207NDB5V1
AK9	IO207PDB5V1
AK10	IO201NDB5V0
AK11	IO201PDB5V0
AK12	IO193NDB4V4
AK13	IO193PDB4V4
AK14	IO197PDB5V0
AK15	IO191NDB4V4
AK16	IO191PDB4V4
AK17	IO189NDB4V4
AK18	IO189PDB4V4
AK19	IO179PPB4V3
AK20	IO175NDB4V2
AK21	IO175PDB4V2
AK22	IO169NDB4V1

FG896	
Pin Number	A3PE3000L Function
M14	GND
M15	GND
M16	GND
M17	GND
M18	GND
M19	GND
M20	VCC
M21	VCCIB2
M22	NC
M23	IO104PPB2V2
M24	IO102PDB2V2
M25	IO102NDB2V2
M26	IO95PDB2V1
M27	IO97NDB2V1
M28	IO101NDB2V2
M29	IO103NDB2V2
M30	IO119PDB3V0
N1	IO276PDB7V0
N2	IO278PDB7V0
N3	IO280PDB7V0
N4	IO284PDB7V1
N5	IO279PDB7V0
N6	IO285NDB7V1
N7	IO287NDB7V1
N8	IO281NDB7V0
N9	IO281PDB7V0
N10	VCCIB7
N11	VCC
N12	GND
N13	GND
N14	GND
N15	GND
N16	GND
N17	GND
N18	GND
N19	GND